**CALL FOR PAPERS**

The IEEE VLSI Test Symposium (VTS) explores emerging trends and novel concepts in test, validation, yield, reliability and security of microelectronic circuits and systems. The 2021 edition of VTS will be an online virtual interactive live event. The VTS Program Committee invites original, unpublished paper submissions for VTS 2021. Proposals for the innovative practices and special sessions tracks are also invited.

**Major topics include but are not limited to:**

- Analog, Mixed-Signal, RF Test
- ATPG & Compression
- Silicon Debug
- Automotive Test & Safety
- Built-In Self-Test (BIST)
- Defect & Current Based Test
- Defect & Fault Tolerance
- Delay & Performance Test
- Design for Testability, Yield or Reliability
- Pre-silicon Design Verification & Validation
- Post-silicon Validation
- Embedded System & Board Test
- Embedded Test Methods
- Emerging Technologies Test and Reliability
- FPGA Test
- Fault Modeling and Simulation
- Hardware Security
- Low-Power IC Test
- Machine Learning in Test, Yield and Reliability
- Microsystems/MEMS/Sensors Test
- Memory Test and Repair
- On-Line Test & Error Correction
- Power & Thermal Issues in Test
- System-on-Chip (SOC) Test
- Test & Reliability of Biomedical Devices
- Test & Reliability of High-Speed I/O
- Test & Reliability of Machine Learning Systems
- Test Quality & Reliability
- Test Standards & Economics
- Test Resource Partitioning
- Transient & Soft Errors
- 2.5D, 3D & SiP Test
- Yield Optimization

**New hot topics:**

- VTS puts particular emphasis on enlarging its scope soliciting submissions on aspects on the following hot topics:
  - Test, Reliability & Security of AI and Neuromorphic Devices
  - Machine Learning for Test
  - Test & Reliability of Machine Learning Systems
  - Test, Reliability & Security in Quantum Computing

**KEY DATES**

- Paper registration: Nov. 29, 2020
- Paper PDF upload: Nov. 29, 2020
- Questions from reviewers to authors: Dec. 11, 2020
- Submission of rebuttal: Dec. 15, 2020
- Notification of acceptance: Dec. 21, 2020

**Submissions**

- Scientific Papers: 6 pages*.
- Industrial Applications short papers: 3 pages*.

*in a standard IEEE two columns format.

Given the unique opportunity of reaching the worldwide test community through a virtual event registration rate for most authors and attendees will be a fraction of our registration rate for VTS’20. VTS 2021 will present a Best Paper Award, a Best Special Session Award, and a Best Innovative Practices Session Award based on the evaluations of reviewers, attendees, and an invited panel of judges. We also plan to organize various Student Activities including the TTTC Best Doctoral Thesis Contest.

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